

**CGWT40N120F2KAD**

V_{CE}	$I_c (T_c=100^\circ\text{C})$	$V_{CE(sat)}$
1200V	40A	1.7V

TO-247

**DESCRIPTION**

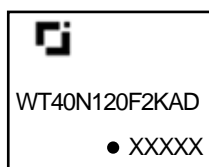
The CGWT40N120F2KAD is used JSCJ's second generation IGBT technology, has advanced Trench and FS (Field Stop) Structure, it's with very low Collector-Emitter Saturation Voltage, can easy to use in parallel.

Features

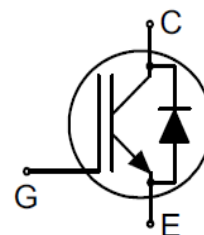
- 1200V breakdown Voltage
- Low $V_{ce(sat)}$ and positive temperature coefficient
- Low switching loss
- With fast and soft recovery freewheeling diode
- Good EMI behavior

Application

- Solar
- UPS & FPC applications
- Welder

MARKING

WT40N120F2KAD = Device code
Solid dot = Green molding compound device, if none, the normal device
XXXX = Code

EQUIVALENT CIRCUIT

Order Code	Package	Marking	Parking
CGWT40N120F2KAD	TO-247	WT40N120F2KAD	Tube

Absolute Maximum Ratings (T_C=25°C unless otherwise noted)

Symbol	Parameter	Value	Units
V _{CES}	Collector-Emitter Voltage	1200	V
V _{GES}	Gate-Emitter Voltage	±20	V
	Gate-Emitter transient voltage	±30	V
I _C	Collector Current	80	A
	Collector Current @T _C =100°C	40	
I _{Cpluse}	Plused Collector Current, tp limited by T _{Jmax}	160	A
I _{LM} ⁽¹⁾	Turn-off latching current	160	A
I _F	Continuous Diode Forward Current	80	A
	Continuous Diode Forward Current @T _C =100°C	40	A
I _{FM}	Diode Pulsed Current, Limited by T _{Jmax}	160	A
P _D	Power Dissipation @T _C =25°C	357	W
	Power Dissipation @T _C =100°C	178	
T _J ⁽²⁾	Operating Junction Temperature	-40 to 175	°C
T _{STG}	Storage Temperature	-55 to 150	°C
T _L	Maximum lead temperature for soldering	260	°C

(1) V_{CC} =600V, V_{GE} = 15 V, T_J ≤ 150 °C.

(2) During overload conditions, allow operation at the maximum junction temperature, T_{vj}=175°C, with a maximum duty cycle of 20% (60s at most)

Thermal Characteristics

Symbol	Parameter	Value	Units
R _{θJC}	Maximum IGBT Junction-to-Case	0.42	°C/W
R _{θJC}	Maximum Diode Junction-to-Case	1.2	°C/W
R _{θJA}	Maximum Junction-to-Ambient	40	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Ration			Unit s
			Min.	Typ.	Max.	
STATIC PARAMETERS						
V _{(BR)CES}	Collector-Emitter Breakdown Voltage	V _{GE} =0V, I _{CE} =1mA	1200	--	--	V
I _{CES}	Zero Gate Voltage Collector Current	V _{GE} =0V, V _{CE} =1200V	--	--	1.0	mA
I _{GES}	Gate-Emitter leakage current	V _{GE} =±20V	--	--	±250	nA
		V _{GE} =±30V	--	--	±500	nA
V _{GE(th)}	Gate-Emitter Threshold Voltage	I _C =250μA, V _{CE} =V _{GE}	4.5	--	7.5	V
V _F	Diode Forward Voltage	I _F =40A, T _J =25°C	--	3.5	--	V
		I _F =40A, T _J =125°C	--	2.4	--	V
		I _F =40A, T _J =150°C	--	2.3	--	V
V _{CE(sat)}	Collector-Emitter Saturation Voltage	I _C =40A, V _{GE} =15V, T _J =25°C	--	1.7	--	V
		I _C =40A, V _{GE} =15V, T _J =125°C	--	2	--	V
		I _C =40A, V _{GE} =15V, T _J =150°C	--	2.1	--	V
DYNAMIC PARAMETERS						
C _{ies}	Input Capacitance	V _{CE} =30V, V _{GE} =0V f=1MHz	--	4225	--	pF
C _{oes}	Output Capacitance		--	125	--	
C _{res}	Reverse Transfer Capacitance		--	27.5	--	
R _g	Gate resistance	V _{GE} =0V, V _{CC} =0V, f=1MHz	--	1	--	Ω
Q _G	Total Gate Charge	V _{CE} =960 V, I _C = 40 A, V _{GE} = 15 V		170.6		nC
Q _{GE}	Gate to Emitter Charge			41		nC
Q _{GC}	Gate to Collector Charge			92.3		nC
SWITCHING PARAMETERS						
t _{d(on)}	Turn-On Delay Time	V _{CE} =600V, I _C =40A, R _g =10Ω, V _{GE} =15V, Inductive Load T _J =25°C	--	41	--	ns
t _r	Current Rise Time		--	93	--	
t _{d(off)}	Turn-Off Delay Time		--	171	--	
t _f	Current Fall Time		--	66	--	
E _{on} ⁽³⁾	Turn-On Switching Energy		--	3	--	mJ
E _{off}	Turn-Off Switching Energy		--	1.4	--	
E _{is}	Total Switching Energy		--	4.4	--	

(3) Including the reverse recovery of the diode.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

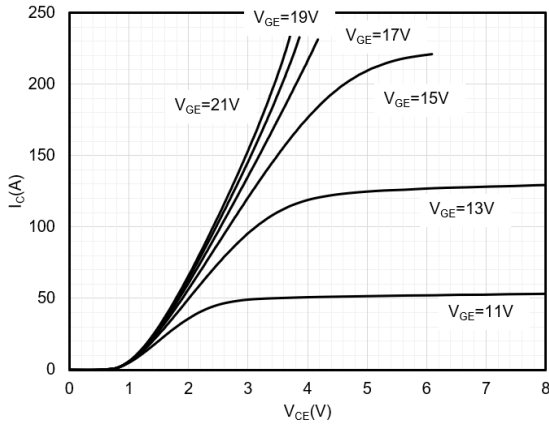


Figure 1: Output Characteristic
($T_j=25^{\circ}\text{C}$)

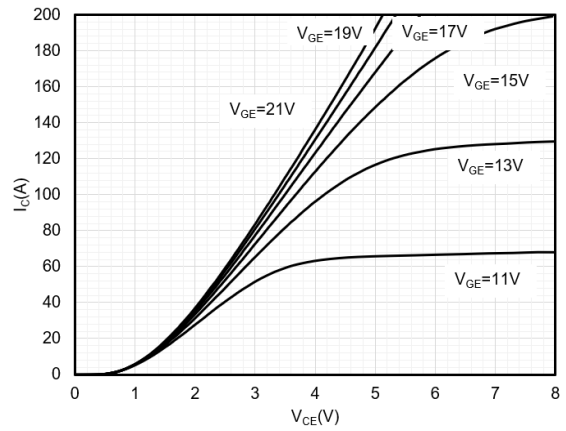


Figure 2: Output Characteristic
($T_j=150^{\circ}\text{C}$)

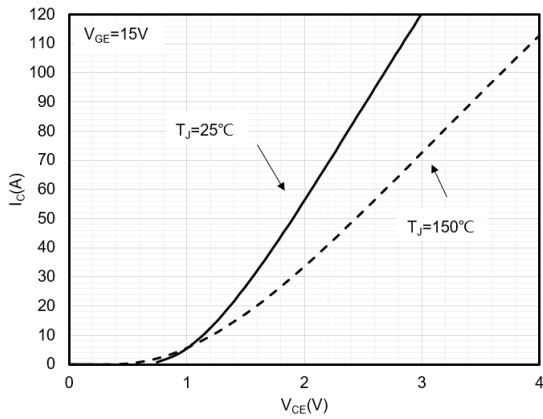


Figure 3: Collector-Emitter Saturation Voltage

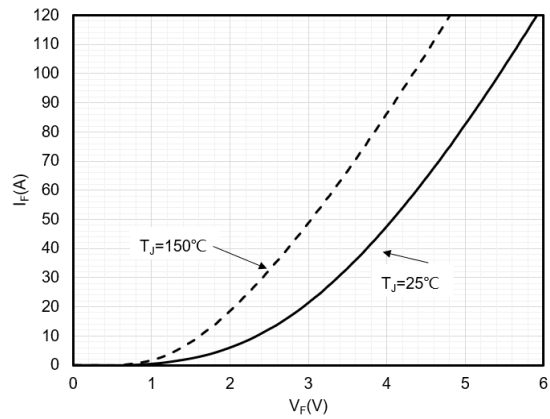


Figure 4: Diode Characteristic

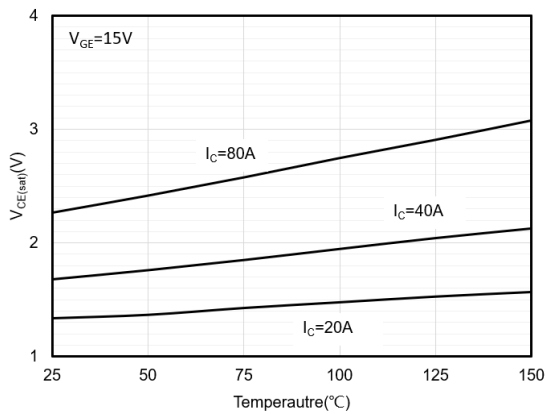


Figure 5: Collector-Emitter Saturation Voltage vs.
Junction Temperature

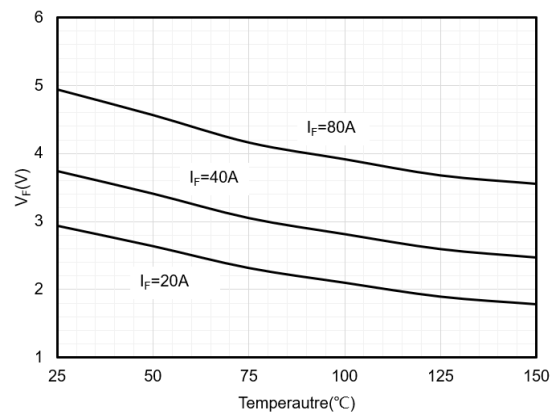


Figure 6: Diode Forward voltage vs. Junction
Temperature

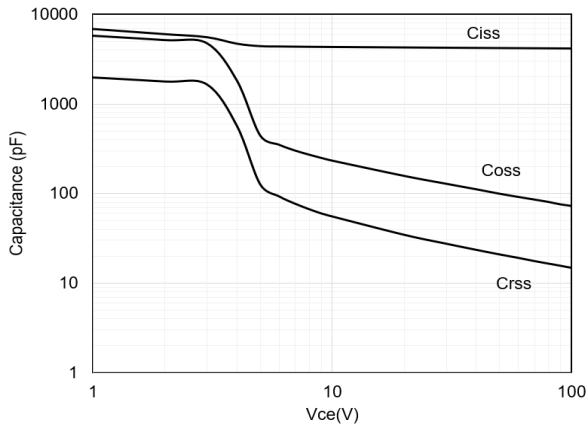


Figure 7: Capacitance Characteristic

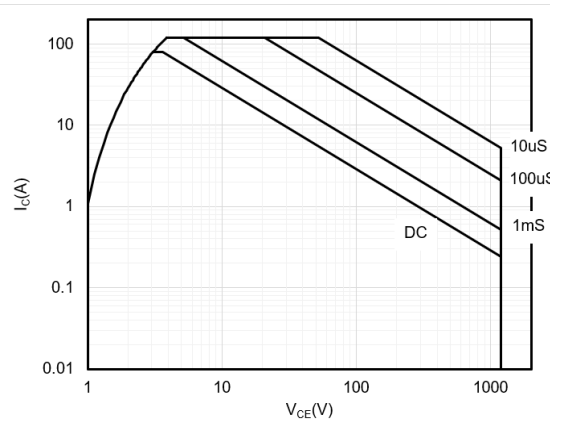


Figure 8: Forward Bias Safe Operating Area
($T_C=25^\circ\text{C}$, $V_{GE}=15\text{V}$)

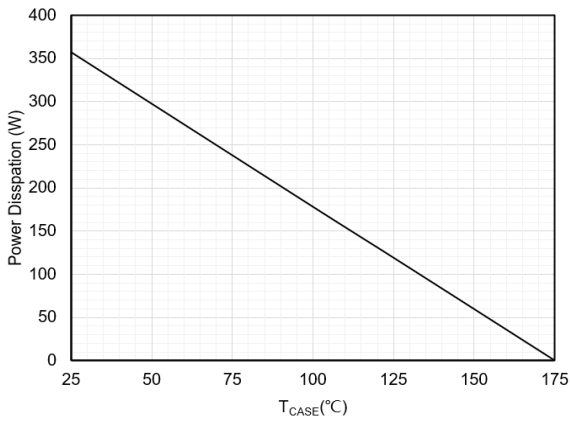


Figure 9: Power Dissipation as a Function of Case

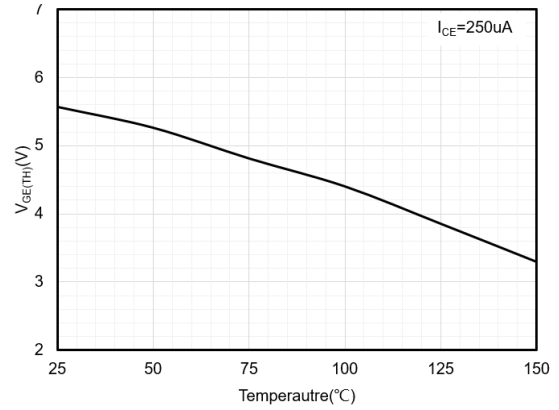


Figure 10: VGE(TH) vs. Tj

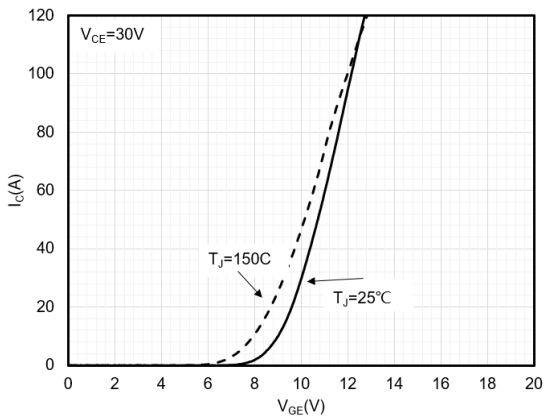


Figure 11: Transfer Characteristic

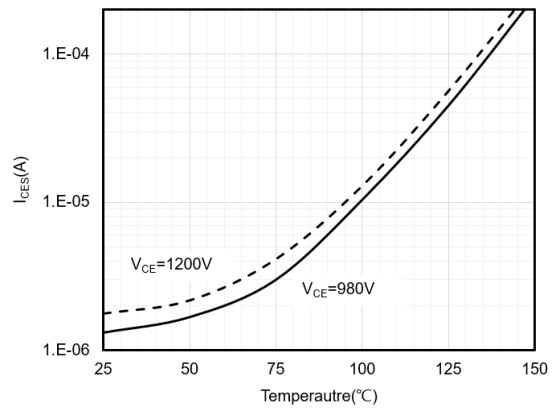


Figure 12: Reverse Leakage Current vs. Tj

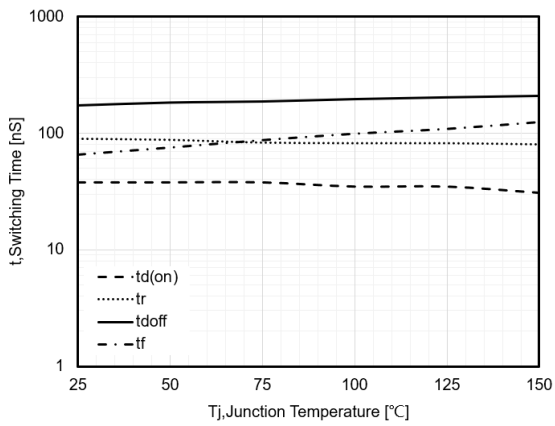


Figure 13 Typical Switching times as a function of Junction Temperature

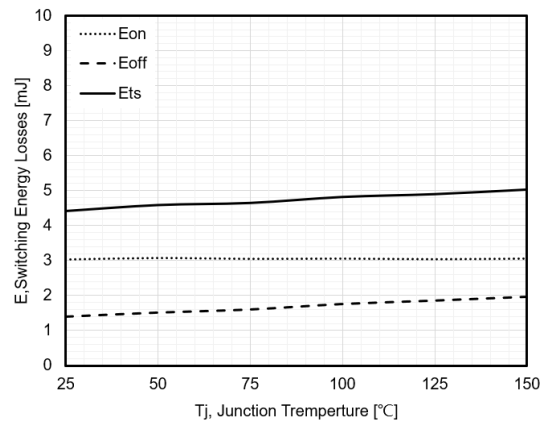


Figure 14 Typical Switching losses as a function of Junction Temperature

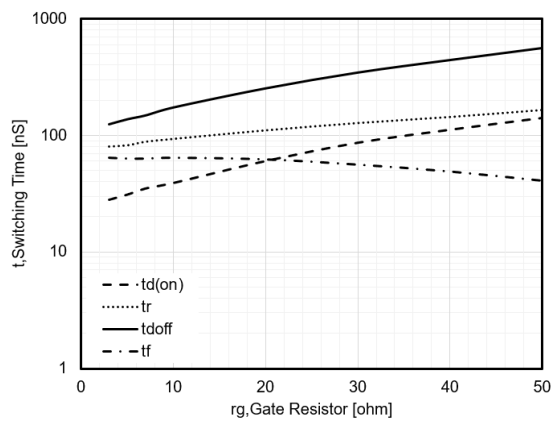


Figure 15 Typical Switching Times as a function of gate resistor

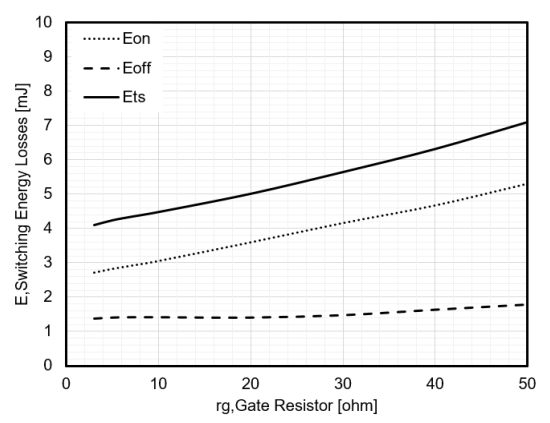


Figure 16 Typical Switching Energy losses as a function of gate resistor

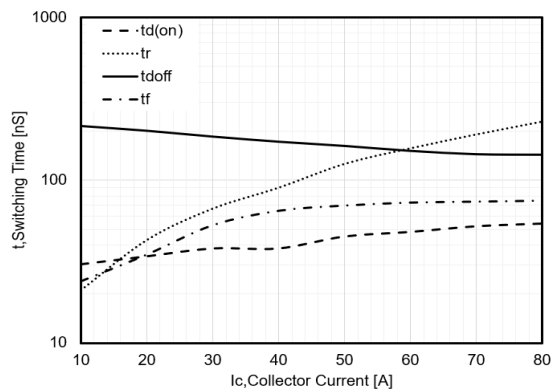


Figure 17 Typical Switching Times as a function of Collector Current

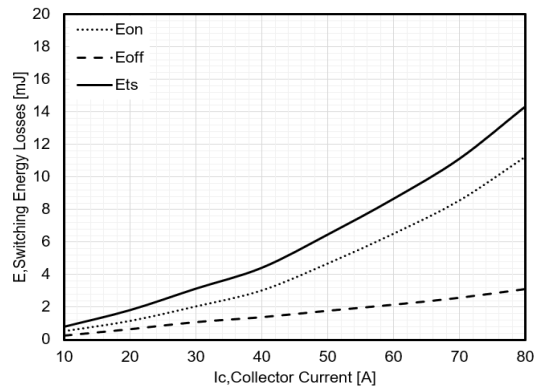


Figure 18 Typical Switching losses as a function of Collector Current

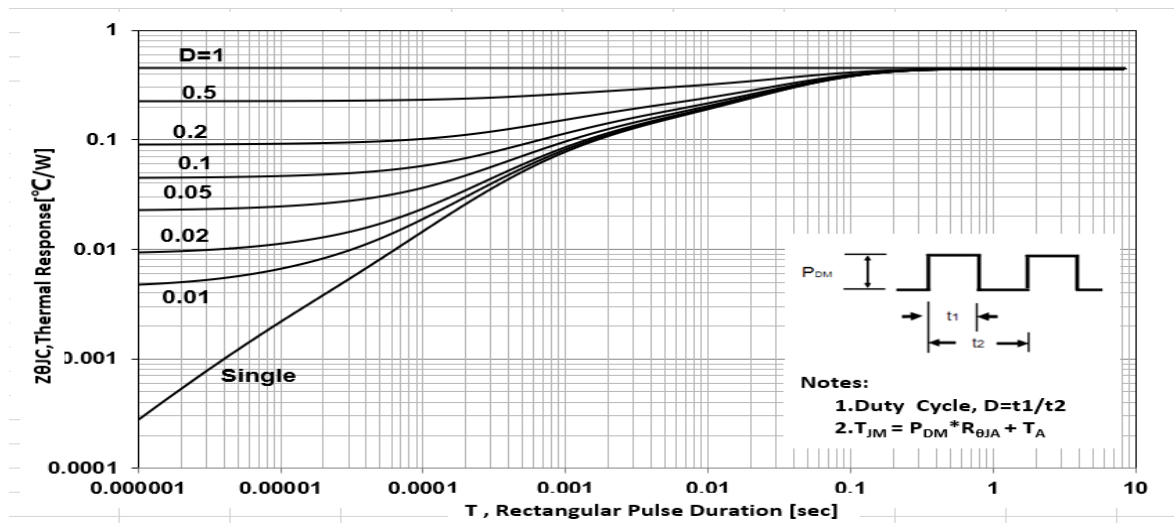
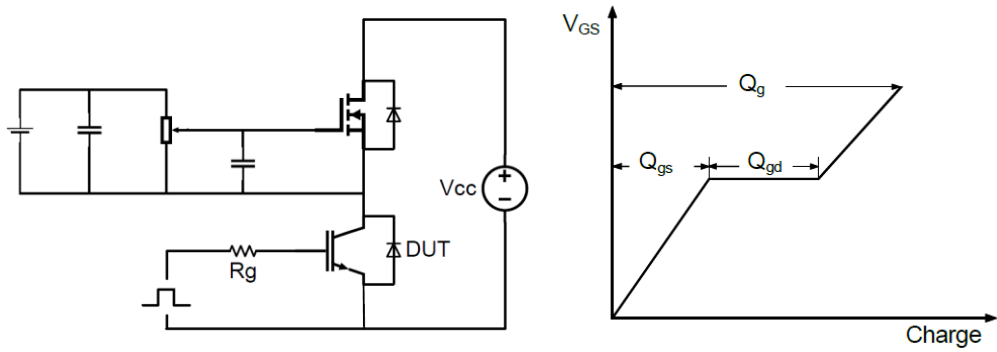


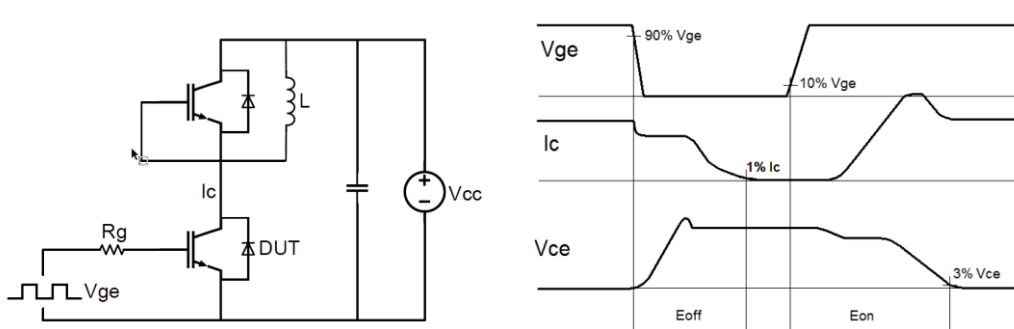
Figure 19 Normalized Transient Thermal Impedance for IGBT

TEST CIRCUIT AND WAVEFORMS

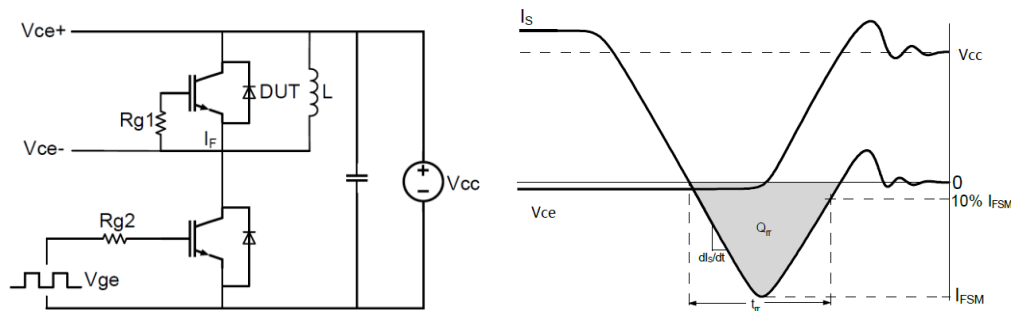
Gate Charge



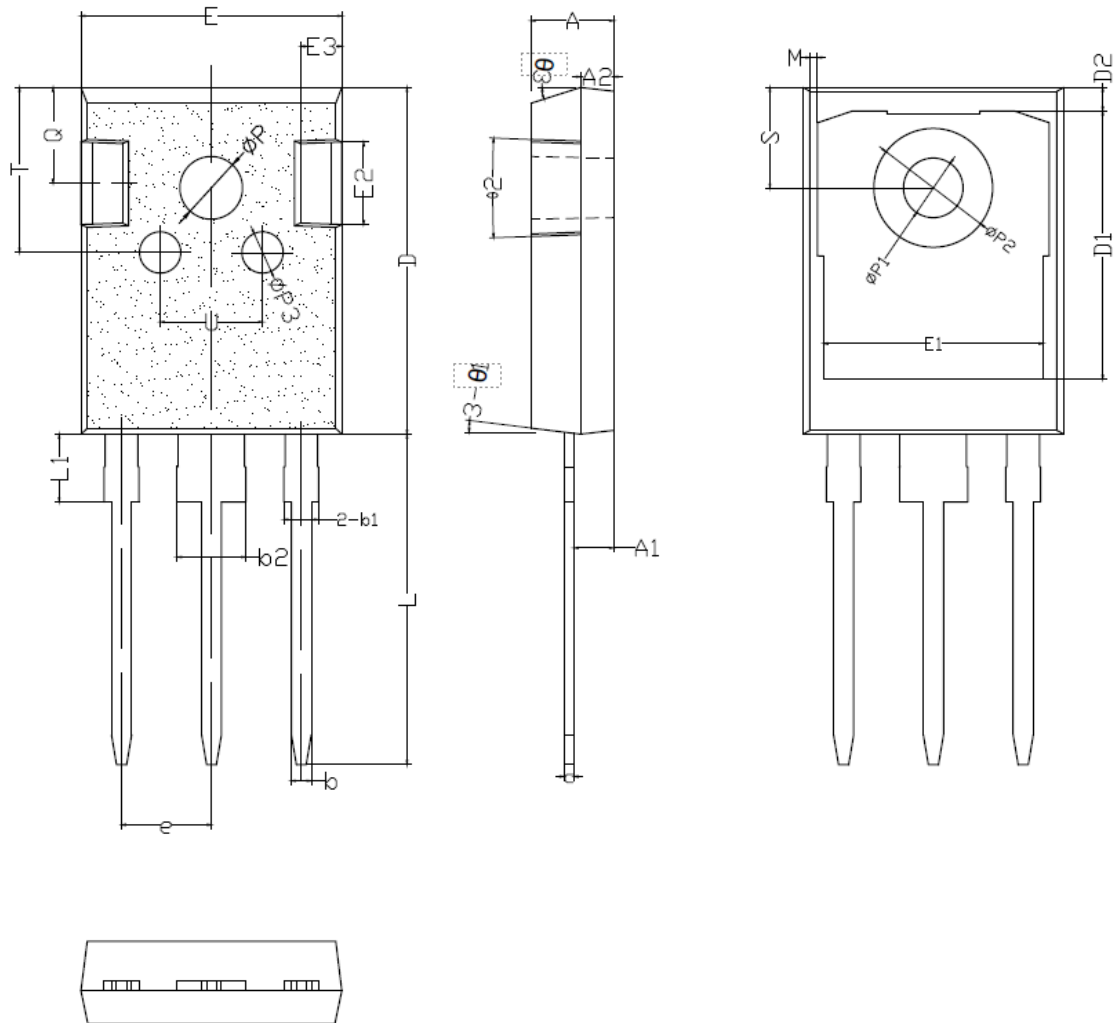
Inductive Switching Test Circuit



Diode Reverse Recovery



TO-247 PACKAGE OUTLINE DIMENSIONS



SYMBOL	mm		
	MIN	NOM	MAX
*A	4.90	5.00	5.10
*A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
*b	1.15	1.20	1.25
*b1	1.95	2.10	2.25
*b2	2.95	3.10	3.25
*c	0.55	0.60	0.65
*D	20.90	21.00	21.10
D1	16.35	16.55	16.75
D2	1.05	1.20	1.35
*E	15.70	15.80	15.90

JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD

E1	13.10	13.25	13.40
E2	4.85	4.95	5.10
E3	2.40	2.50	2.60
*e	5.40	5.44	5.48
*L	19.80	19.98	20.15
*L1	-	-	4.30
*ΦP	3.40	3.50	3.60
*ΦP1	6.90	7.10	7.30
ΦP2	2.40	2.50	2.60
ΦP3	2.40	2.50	2.60
Q	5.60	5.80	6.00
*S	6.05	6.15	6.25
T	9.80	10.00	10.20
U	6.00	6.20	6.40
θ1	5°	7°	9°
θ2	1°	3°	5°
θ3	13°	15°	17°
*为管控尺寸			